

## MOS FIELD EFFECT TRANSISTOR $\mu$ PA1810

### P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

#### **DESCRIPTION**

The  $\mu$ PA1810 is a switching device which can be driven directly by a 2.5 V power source.

The  $\mu$ PA1810 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

#### **FEATURES**

- Can be driven by a 2.5 V power source
- · Low on-state resistance

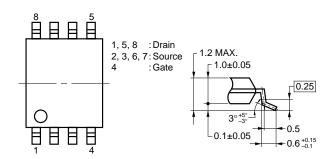
RDS(on)1 = 55 m $\Omega$  MAX. (VGS = -4.5 V, ID = -2.0 A) RDS(on)2 = 60 m $\Omega$  MAX. (VGS = -4.0 V, ID = -2.0 A)

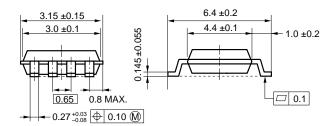
RDS(on)3 = 100 m $\Omega$  MAX. (VGS = -2.5 V, ID = -2.0 A)

#### ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1810GR-9JG	Power TSSOP8

#### PACKAGE DRAWING (Unit: mm)

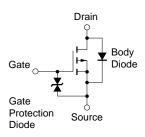




#### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25$ °C)

Drain to Source Voltage	VDSS	-12	V
Gate to Source Voltage	Vgss	-10/+5	V
Drain Current (DC)	ID(DC)	±4.0	Α
Drain Current (pulse) Note1	D(pulse)	±16	Α
Total Power Dissipation Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

#### **EQUIVALENT CIRCUIT**



- **Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1 %
  - 2. Mounted on ceramic substrate of 5000 mm<sup>2</sup> x 1.1 mm

#### Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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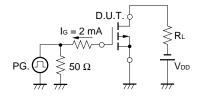
#### **ELECTRICAL CHARACTERISTICS (TA = 25 °C)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V <sub>DS</sub> = -12 V, V <sub>GS</sub> = 0 V			-10	μΑ
Gate Leakage Current	Igss	Vgs = ±10 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-0.5	-0.8	-1.5	V
Forward Transfer Admittance	yfs	$V_{DS} = -10 \text{ V}, I_{D} = -2.0 \text{ A}$	2.5	8.5		S
Drain to Source On-state Resistance	RDS(on)1	$V_{GS} = -4.5  V,  I_{D} = -2.0  A$		41	55	mΩ
	RDS(on)2	$V_{GS} = -4.0 \text{ V}, I_{D} = -2.0 \text{ A}$		43	60	mΩ
	RDS(on)3	$V_{GS} = -2.5  \text{V},  I_{D} = -2.0  \text{A}$		71	100	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = -10 V		1100		pF
Output Capacitance	Coss	V <sub>G</sub> s = 0 V		750		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		240		pF
Turn-on Delay Time	td(on)	V <sub>DD</sub> = -10 V		40		ns
Rise Time	<b>t</b> r	ID = -2.0 A		100		ns
Turn-off Delay Time	t <sub>d(off)</sub>	V <sub>GS(on)</sub> = -4.0 V		90		ns
Fall Time	tf	$R_G = 5 \Omega$		70		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = -10 V		35		nC
Gate to Source Charge	Qss	ID = -4.0 A		5		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>GS</sub> = -4.0 V		16		nC
Diode Forward Voltage	V <sub>F(S-D)</sub>	IF = 4.0 A, VGS = 0 V		0.75		V
Reverse Recovery Time	trr	IF = 4.0 A, VGS = 0 V		50		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μS		35		nC

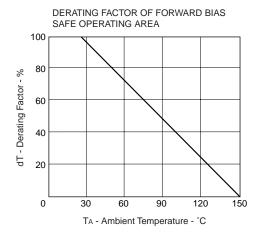
#### **TEST CIRCUIT 1 SWITCHING TIME**

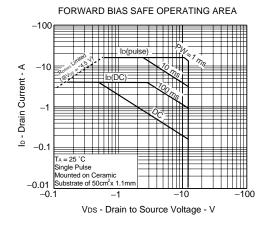
# PG. $\bigcap_{R_G} R_G = 10 \ \Omega$ $V_{DD}$ $V_{GS}$ 0 10 % $V_{GS}(on)$ $V_{GS}(on)$

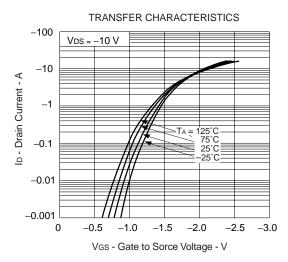
#### **TEST CIRCUIT 2 GATE CHARGE**

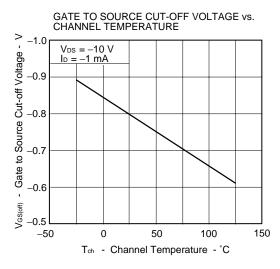


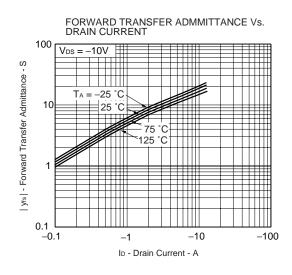
#### TYPICAL CHARACTERISTICS (TA = 25 °C)

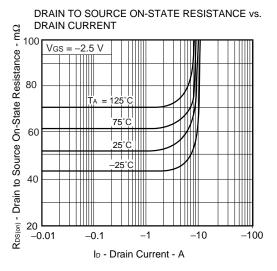


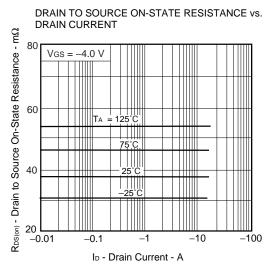


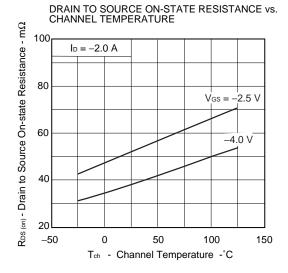


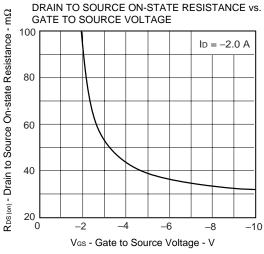


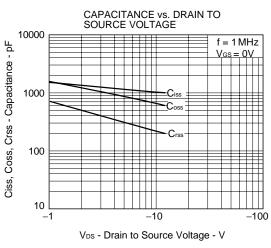


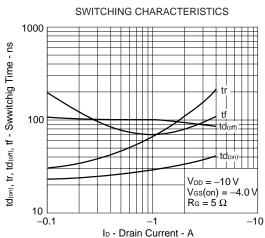


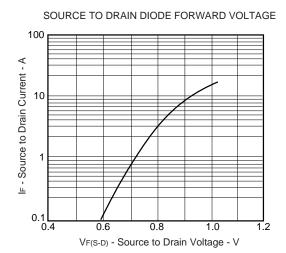




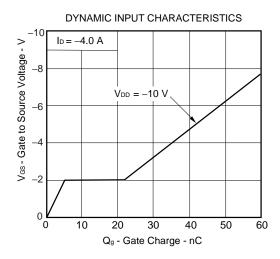




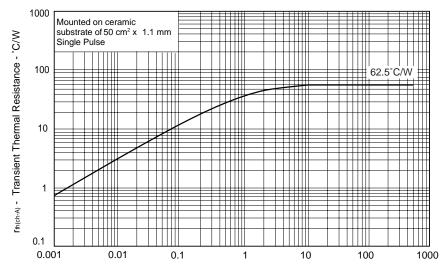




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#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



PW - Pulse Width - s

[MEMO]

**NEC**  $\mu$  PA1810

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